

N-Channel Enhancement Mode Field Effect Transistor

Product Summary

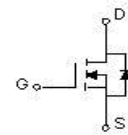
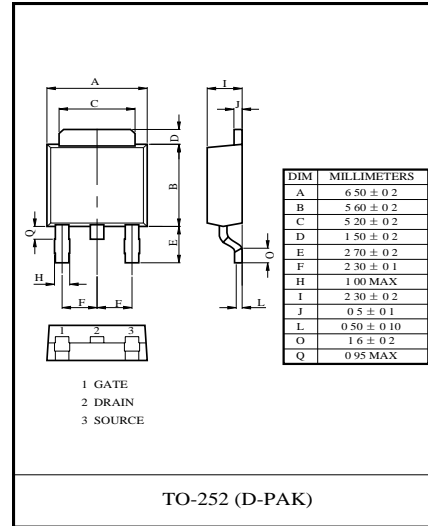
- V_{DS} 100V
- I_D 45A
- $R_{DS(ON)}$ (at $V_{GS}=10V$) < 17 mohm
- $R_{DS(ON)}$ (at $V_{GS}=4.5V$) < 21.5 mohm
- 100% UIS Tested
- 100% \square VDS Tested

General Description

- Low $R_{DS(on)}$ & FOM
- Extremely low switching loss
- Excellent stability and uniformity
- Fast switching and soft recovery

Applications

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-source Voltage	V_{DS}	100	V
Gate-source Voltage	V_{GS}	±20	V
Drain Current	I_D	$T_C=25^\circ\text{C}$	45
		$T_C=100^\circ\text{C}$	28.5
Pulsed Drain Current ^A	I_{DM}	180	A
Avalanche energy ^B	EAS	81	mJ
Total Power Dissipation ^C	P_D	$T_C=25^\circ\text{C}$	72
		$T_C=100^\circ\text{C}$	28.8
Junction and Storage Temperature Range	T_J, T_{STG}	-55~+150	°C

■ Thermal resistance

Parameter	Symbol	Typ	Max	Units
Thermal Resistance Junction-to-Ambient ^D	$R_{\theta JA}$	15	20	°C/W
Thermal Resistance Junction-to-Ambient ^D		Steady-State	40	
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	1.35	1.7	



IRF540D

■ Electrical Characteristics ($T_j=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	100			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=100V, V_{GS}=0V$			1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1	1.8	3	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$		14	17	m Ω
		$V_{GS}=4.5V, I_D=20A$		17	21.5	m Ω
Diode Forward Voltage	V_{SD}	$I_S=20A, V_{GS}=0V$			1.3	V
Maximum Body-Diode Continuous Current	I_S				45	A
Gate resistance	R_G	$f=1\text{ MHz, Open drain}$		1		Ω
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{DS}=50V, V_{GS}=0V, f=1\text{ MHz}$		1135		pF
Output Capacitance	C_{oss}			399		
Reverse Transfer Capacitance	C_{rss}			18		
Switching Parameters						
Total Gate Charge	Q_g	$V_{GS}=10V, V_{DS}=50V, I_D=25A$		16		nC
Gate-Source Charge	Q_{gs}			5.6		
Gate-Drain Charge	Q_{gd}			2.4		
Reverse Recovery Charge	Q_{rr}	$I_F=20A, di/dt=100A/\mu s$		42		nC
Reverse Recovery Time	t_{rr}			39.8		
Turn-on Delay Time	$t_{D(on)}$	$V_{GS}=10V, V_{DD}=50V, I_D=25A$ $R_{GEN}=2.2\Omega$		39.2		ns
Turn-on Rise Time	t_r			11		
Turn-off Delay Time	$t_{D(off)}$			53.2		
Turn-off fall Time	t_f			15.8		

A. Repetitive rating; pulse width limited by max. junction temperature.

B. $V_{DD}=50V, V_{GS}=10V, L=5mH, I_{AS}=5.7A$.

C. Pd is based on max. junction temperature, using junction-case thermal resistance.

D. The value of RqJA is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation PDSM is based on RqJA $\leq 10s$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

Typical Performance Characteristics

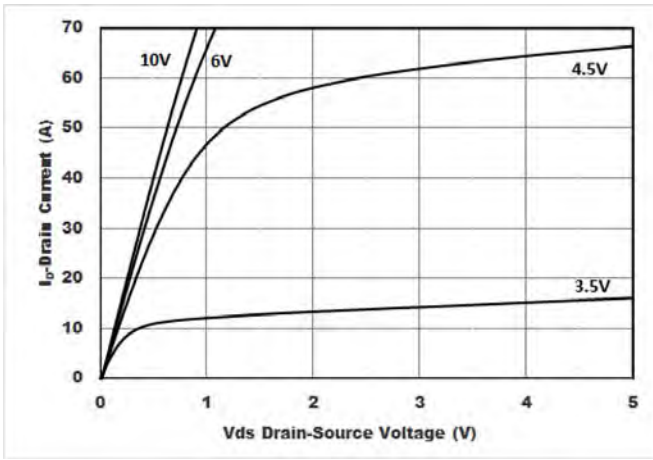


Figure1. Output Characteristics

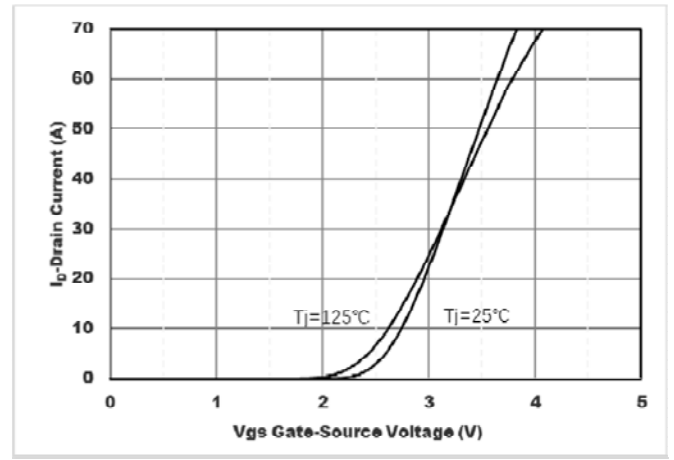


Figure2. Transfer Characteristics

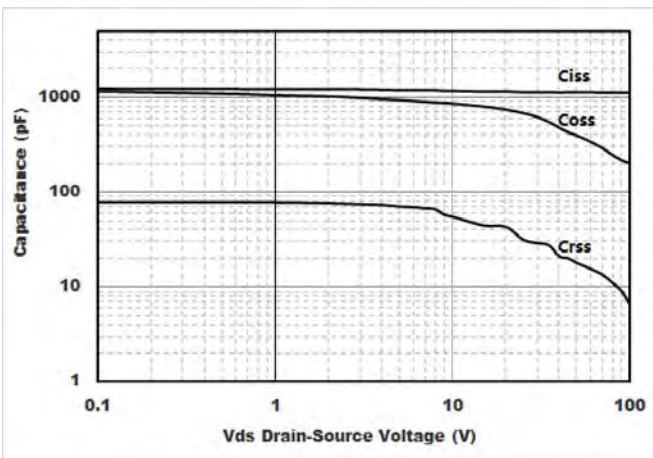


Figure3. Capacitance Characteristics

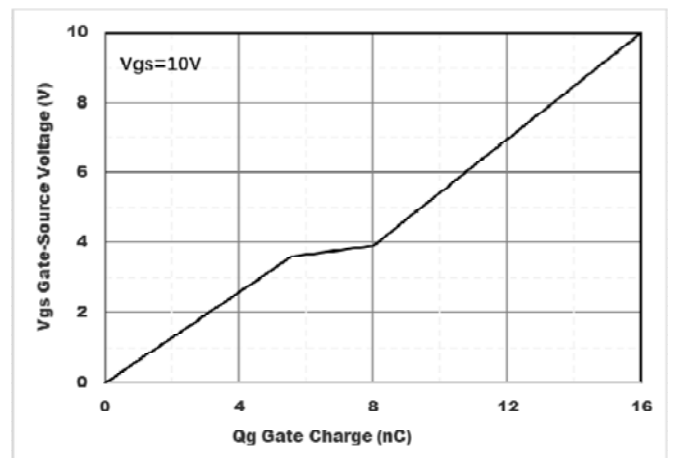


Figure4. Gate Charge

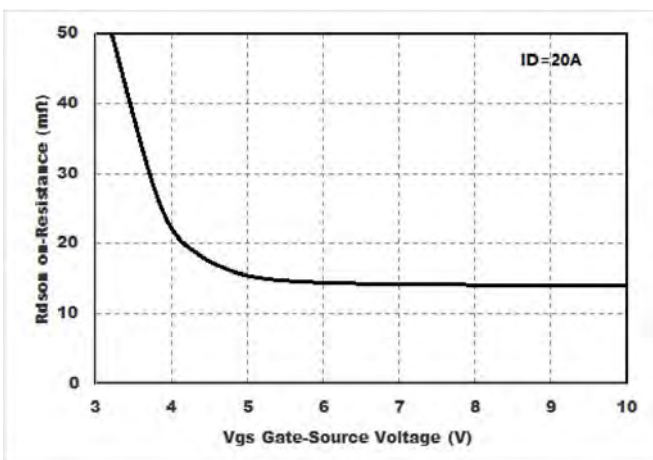


Figure5. : On-Resistance vs. Drain Current and Gate Voltage

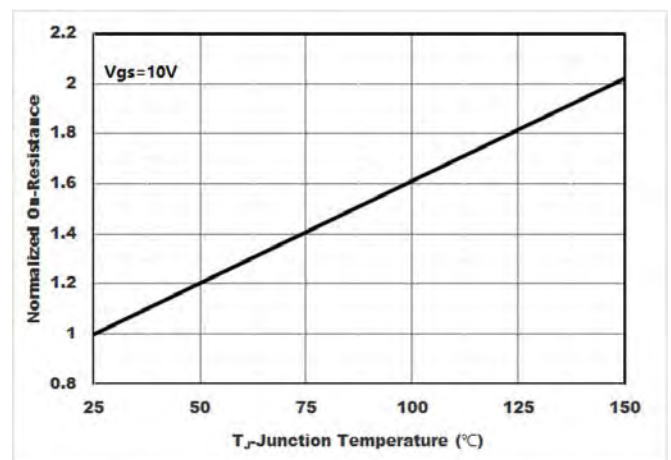


Figure6. Normalized On-Resistance

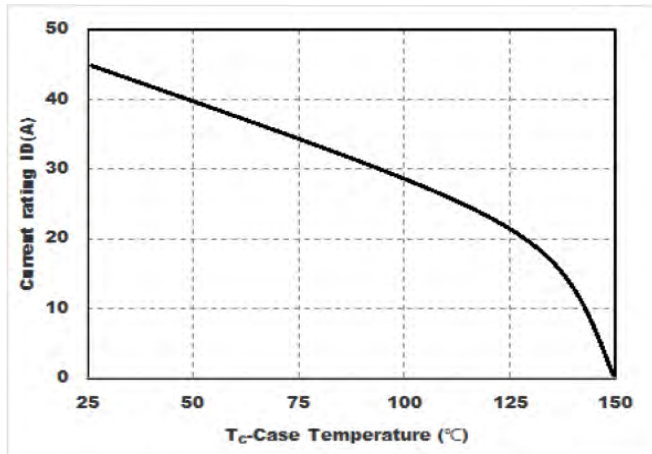


Figure7. Drain current

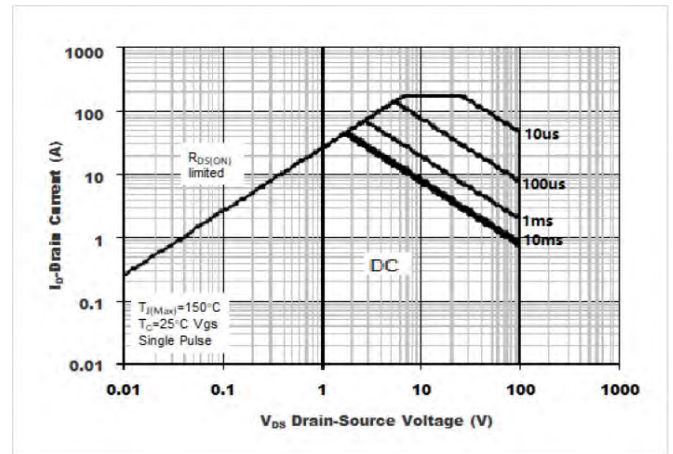


Figure8.Safe Operation Area

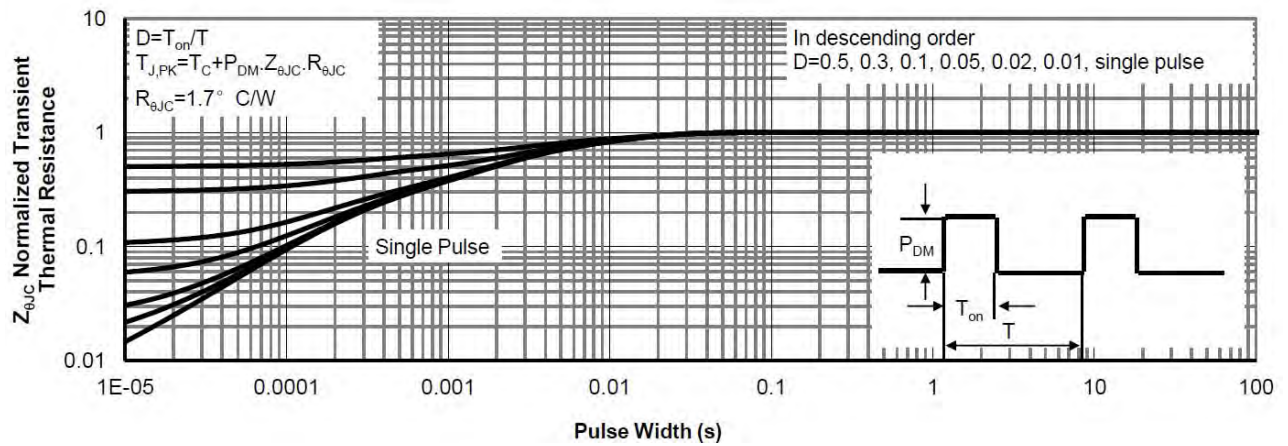


Figure9.Normalized Maximum Transient thermal impedance